

Notice of References Cited

Application/Control No.

10/088,206

Applicant(s)/Patent Under
Reexamination
DEWAELE, LUC

Examiner

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Art Unit

2859

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6220750	04-2001	Palti	374
	B	US-5001925	03-1991	Turek	73
	C	US-5318077	06-1994	Yamashita	139
	D	US-4336708	06-1982	Hobgood et al.	73
	E	US-5281793	01-1994	Gavin et al.	219
	F	US-3559726	02-1971	Menasoff	73
	G	US-3926053	12-1975	Schurrer et al.	324
	H	US-5939978	08-1999	Kyrtos	340
	I	US-6000844	12-1999	Cramer et al.	374
	J	US-5123752	06-1992	Paz-Pujalt et al.	374
	K	US-4674326	06-1987	Reinecke	73
	L	US-4046990	09-1977	White	219
	M	US-5352038	10-1994	Schmidt et al.	374

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JA0209329	09-1986	JA	---	374
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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